

SN54HC4020, SN74HC4020

14-BIT ASYNCHRONOUS BINARY COUNTERS

SCLS158C – DECEMBER 1982 – REVISED FEBRUARY 2000

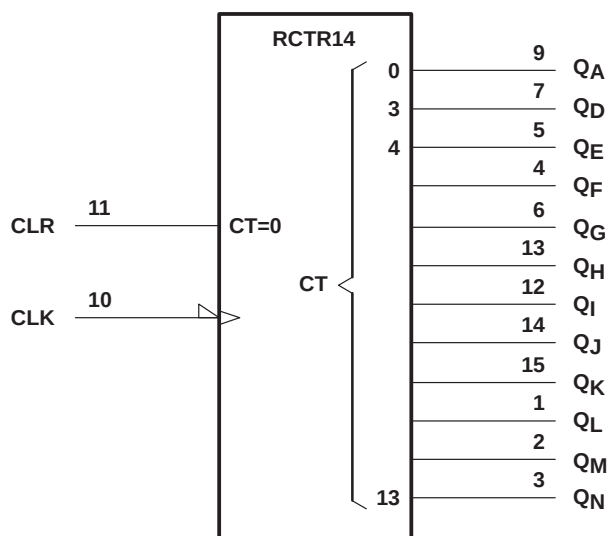
- Package Options Include Plastic Small-Outline (D), Shrink Small-Outline (DB), Thin Shrink Small-Outline (PW), and Ceramic Flat (W) Packages, Ceramic Chip Carriers (FK), and Standard Plastic (N) and Ceramic (J) DIPs

description

These devices are 14-stage binary ripple-carry counters that advance on the negative-going edge of the clock pulse. The counters are reset to zero (all outputs low) independently of the clock (CLK) input when the clear (CLR) input goes high.

The SN54HC4020 is characterized for operation over the full military temperature range of -55°C to 125°C . The SN74HC4020 is characterized for operation from -40°C to 85°C .

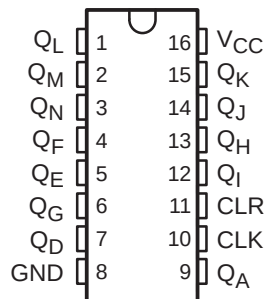
logic symbol†



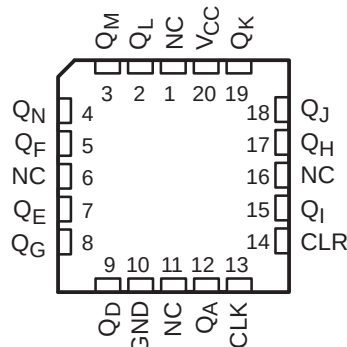
† This symbol is in accordance with ANSI/IEEE Std 91-1984 and IEC Publication 617-12.

Pin numbers shown are for the D, DB, J, N, PW, and W packages.

SN54HC4020 . . . J OR W PACKAGE
SN74HC4020 . . . D, DB, N, OR PW PACKAGE
(TOP VIEW)



SN54HC4020 . . . FK PACKAGE
(TOP VIEW)



NC – No internal connection



Please be aware that an important notice concerning availability, standard warranty, and use in critical applications of Texas Instruments semiconductor products and disclaimers thereto appears at the end of this data sheet.

PRODUCTION DATA information is current as of publication date. Products conform to specifications per the terms of Texas Instruments standard warranty. Production processing does not necessarily include testing of all parameters.

**TEXAS
INSTRUMENTS**

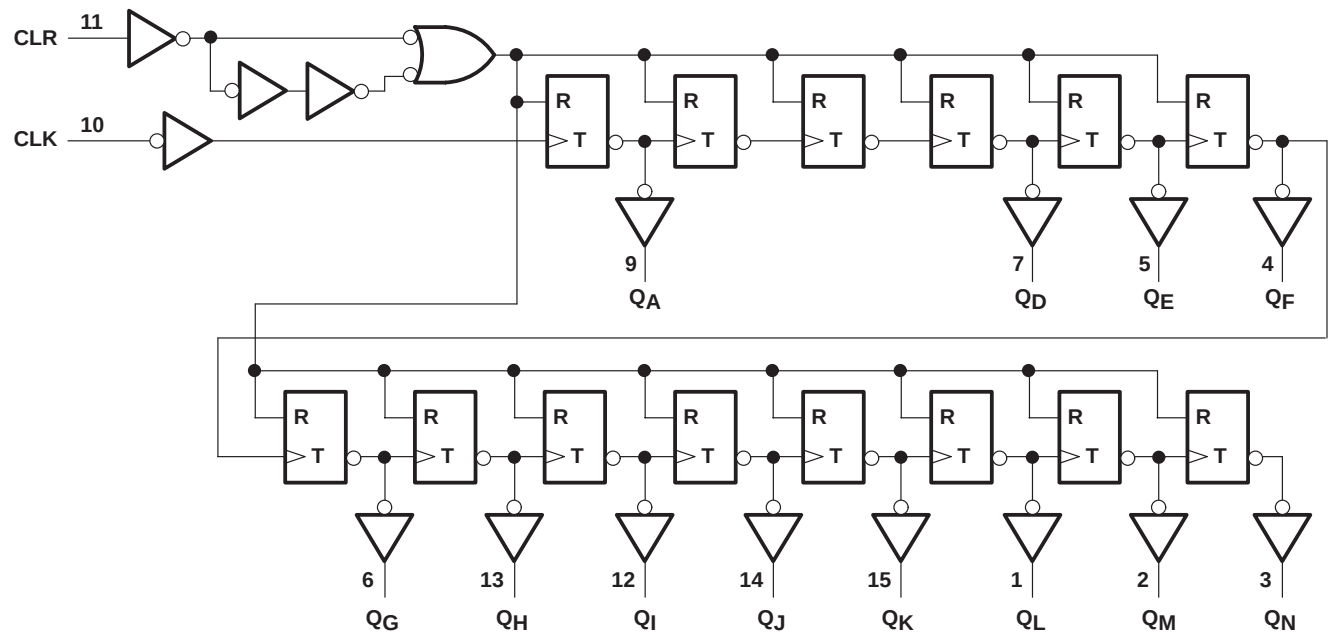
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On products compliant to MIL-PRF-38535, all parameters are tested unless otherwise noted. On all other products, production processing does not necessarily include testing of all parameters.

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logic diagram (positive logic)



Pin numbers shown are for the D, DB, J, N, PW, and W packages.

absolute maximum ratings over operating free-air temperature range†

Supply voltage range, V_{CC}	-0.5 V to 7 V
Input clamp current, I_{IK} ($V_I < 0$ or $V_I > V_{CC}$) (see Note 1)	± 20 mA
Output clamp current, I_{OK} ($V_O < 0$ or $V_O > V_{CC}$) (see Note 1)	± 20 mA
Continuous output current, I_O ($V_O = 0$ to V_{CC})	± 25 mA
Continuous current through V_{CC} or GND	± 50 mA
Package thermal impedance, θ_{JA} (see Note 2):	
D package	73°C/W
DB package	82°C/W
N package	67°C/W
PW package	108°C/W
Storage temperature range, T_{stg}	-65°C to 150°C

† Stresses beyond those listed under “absolute maximum ratings” may cause permanent damage to the device. These are stress ratings only, and functional operation of the device at these or any other conditions beyond those indicated under “recommended operating conditions” is not implied. Exposure to absolute-maximum-rated conditions for extended periods may affect device reliability.

NOTES: 1. The input and output voltage ratings may be exceeded if the input and output current ratings are observed.
2. The package thermal impedance is calculated in accordance with JESD 51.

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recommended operating conditions (see Note 3)

			SN54HC4020			SN74HC4020			UNIT
			MIN	NOM	MAX	MIN	NOM	MAX	
V _{CC}	Supply voltage		2	5	6	2	5	6	V
V _{IH}	High-level input voltage	V _{CC} = 2 V	1.5			1.5			V
		V _{CC} = 4.5 V	3.15			3.15			
		V _{CC} = 6 V	4.2			4.2			
V _{IL}	Low-level input voltage	V _{CC} = 2 V	0		0.5	0		0.5	V
		V _{CC} = 4.5 V	0		1.35	0		1.35	
		V _{CC} = 6 V	0		1.8	0		1.8	
V _I	Input voltage		0		V _{CC}	0		V _{CC}	V
V _O	Output voltage		0		V _{CC}	0		V _{CC}	V
t _t	Input transition (rise and fall) time	V _{CC} = 2 V	0		1000	0		1000	ns
		V _{CC} = 4.5 V	0		500	0		500	
		V _{CC} = 6 V	0		400	0		400	
T _A	Operating free-air temperature		–55		125	–40		85	°C

NOTE 3: All unused inputs of the device must be held at V_{CC} or GND to ensure proper device operation. Refer to the TI application report, *Implications of Slow or Floating CMOS Inputs*, literature number SCBA004.

electrical characteristics over recommended operating free-air temperature range (unless otherwise noted)

PARAMETER	TEST CONDITIONS		V _{CC}	T _A = 25°C			SN54HC4020		SN74HC4020		UNIT
				MIN	TYP	MAX	MIN	MAX	MIN	MAX	
V _{OH}	V _I = V _{IH} or V _{IL}	I _{OH} = –20 µA	2 V	1.9	1.998		1.9		1.9		V
			4.5 V	4.4	4.499		4.4		4.4		
			6 V	5.9	5.999		5.9		5.9		
		I _{OH} = –4 mA	4.5 V	3.98	4.3		3.7		3.84		
		I _{OH} = –5.2 mA	6 V	5.48	5.8		5.2		5.34		
V _{OL}	V _I = V _{IH} or V _{IL}	I _{OL} = 20 µA	2 V		0.002	0.1		0.1		0.1	V
			4.5 V		0.001	0.1		0.1		0.1	
			6 V		0.001	0.1		0.1		0.1	
		I _{OL} = 4 mA	4.5 V		0.17	0.26		0.4		0.33	
		I _{OL} = 5.2 mA	6 V		0.15	0.26		0.4		0.33	
I _I	V _I = V _{CC} or 0		6 V		±0.1	±100		±1000		±1000	nA
I _{CC}	V _I = V _{CC} or 0, I _O = 0		6 V			8		160		80	µA
C _i			2 V to 6 V		3	10		10		10	pF



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timing requirements over recommended operating free-air temperature range (unless otherwise noted)

			V _{CC}	T _A = 25°C		SN54HC4020		SN74HC4020		UNIT
				MIN	MAX	MIN	MAX	MIN	MAX	
f _{clock}	Clock frequency		2 V	0	5.5	0	3.7	0	4.3	MHz
			4.5 V	0	28	0	19	0	22	
			6 V	0	33	0	22	0	25	
t _w	Pulse duration		CLK high or low	2 V	90	135		115	ns	
				4.5 V	18	27		23		
				6 V	15	23		20		
	CLR high	2 V	70	105		90				
		4.5 V	14	21		18				
		6 V	12	18		25				
t _{su}	Setup time, CLR inactive before CLK↓		2 V	60	90		75	ns		
			4.5 V	12	18		15			
			6 V	10	15		13			

switching characteristics over recommended operating free-air temperature range, C_L = 50 pF (unless otherwise noted) (see Figure 1)

PARAMETER	FROM (INPUT)	TO (OUTPUT)	V _{CC}	T _A = 25°C			SN54HC4020		SN74HC4020		UNIT
				MIN	TYP	MAX	MIN	MAX	MIN	MAX	
f _{max}			2 V	5.5	10		3.7		4.3		MHz
			4.5 V	28	45		19		22		
			6 V	33	53		22		25		
t _{pd}	CLK	Q _A	2 V		62	150		225		190	ns
			4.5 V		16	30		45		38	
			6 V		12	26		38		32	
t _{PHL}	CLR	Any	2 V		63	140		210		175	ns
			4.5 V		17	28		42		35	
			6 V		13	24		36		30	
t _t		Any	2 V		28	75		110		95	ns
			4.5 V		8	15		22		19	
			6 V		6	13		19		16	

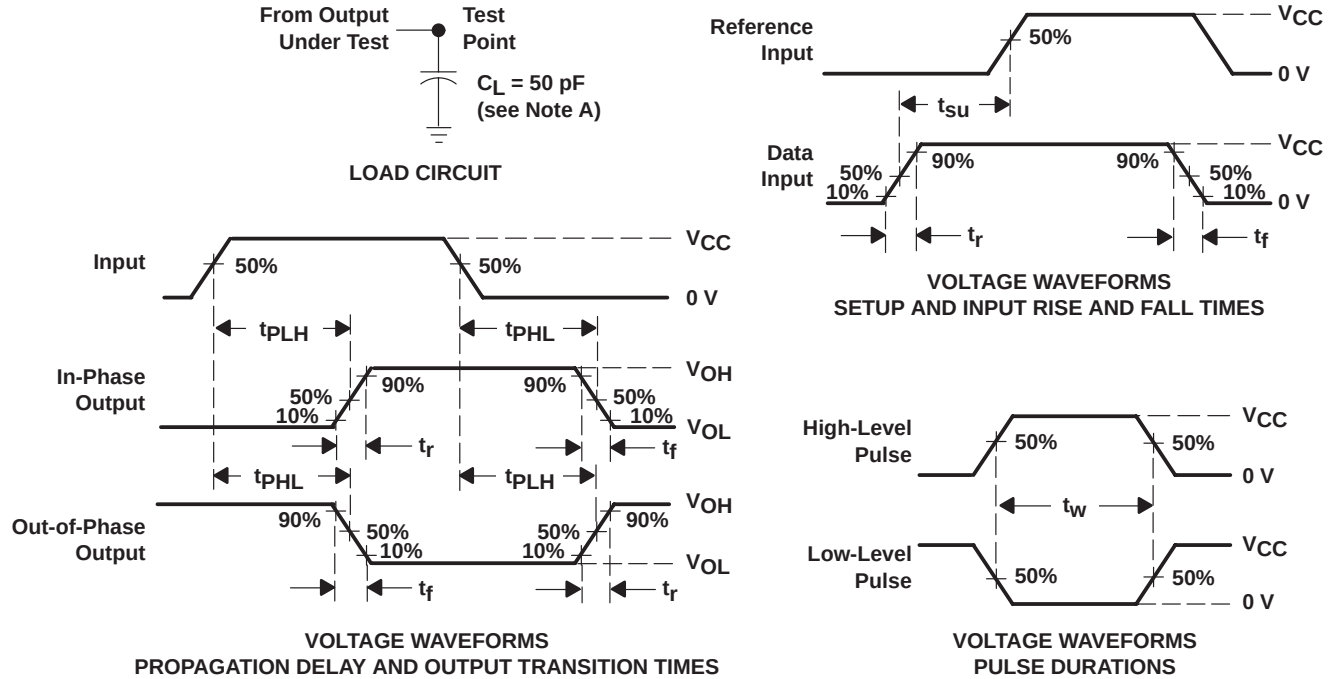
operating characteristics, T_A = 25°C

PARAMETER	TEST CONDITIONS	TYP	UNIT
C _{pd} Power dissipation capacitance	No load	88	pF



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PARAMETER MEASUREMENT INFORMATION



- NOTES: A. C_L includes probe and test-fixture capacitance.
 B. Phase relationships between waveforms were chosen arbitrarily. All input pulses are supplied by generators having the following characteristics: $PRR \leq 1 \text{ MHz}$, $Z_O = 50 \Omega$, $t_r = 6 \text{ ns}$, $t_f = 6 \text{ ns}$.
 C. For clock inputs, f_{max} is measured when the input duty cycle is 50%.
 D. The outputs are measured one at a time with one input transition per measurement.
 E. t_{PLH} and t_{PHL} are the same as t_{pd} .

Figure 1. Load Circuit and Voltage Waveforms

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